

SIGC14T60SNC

IGBT Chip in NPT-technology

FEATURES:

- 600V NPT technology
- 100µm chip
- short circuit prove
- positive temperature coefficient
- easy paralleling

This chip is used for:

• SGP15N60



Applications:

• drives

| Chip Type | V _{CE} | I _{Cn} | Die Size | Package | Ordering Code |
|--------------|-----------------|-----------------|---------------------------|--------------|-----------------------|
| SIGC14T60SNC | 600V | 15A | 3.8 x 3.8 mm ² | sawn on foil | Q67041-A4665- A001 |
| SIGC14T60SNC | 600V | 15A | 3.8 x 3.8 mm ² | unsawn | Q67041-A4665- A002 |

MECHANICAL PARAMETER:

| Raster size | 3.8 x 3.8 | | |
|---------------------------------|---|-----|--|
| Area total / active | 14.44 / 10.7 | | |
| Emitter pad size | 1.89 x 2.19 | | |
| Gate pad size | 0.7 x 1.09 | | |
| Thickness | 100 | μm | |
| Wafer size | 150 | mm | |
| Flat position | 270 | deg | |
| Max.possible chips per wafer | 1032 | | |
| Passivation frontside | Photoimide | | |
| Emitter metallization | 3200 nm Al Si 1% | | |
| Collector metallization | 1400 nm Ni Ag -system suitable for epoxy and soft solder die bonding | | |
| Die bond | electrically conductive glue or solder | | |
| Wire bond | AI, ≤500μm | | |
| Reject Ink Dot Size | Ø 0.65mm; max 1.2mm | | |
| Recommended Storage Environment | store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C | | |



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MAXIMUM RATINGS:

| Parameter | Symbol | Value | Unit |
|---|--------------------|------------------|------|
| Collector-emitter voltage, T _j =25 °C | V _{CE} | 600 | V |
| DC collector current, limited by T _{jmax} | I _C | 1) | А |
| Pulsed collector current, t _p limited by T _{jmax} | I _{cpuls} | 45 | Α |
| Gate emitter voltage | V _{GE} | ±20 | V |
| Operating junction and storage temperature | T_{j}, T_{stg} | -55 + 150 | °C |

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

| Parameter | Symbol | Conditions | Value | | | Unit |
|--------------------------------------|----------------------|--|-------|------|------|------|
| Tarameter | Cymbol | | min. | typ. | max. | 01 |
| Collector-emitter breakdown voltage | V _{(BR)CES} | V _{GE} =0V, I _C =500μA | 600 | | | |
| Collector-emitter saturation voltage | V _{CE(sat)} | V _{GE} =15V, I _C =15A | 1.6 | 2 | 2.5 | V |
| Gate-emitter threshold voltage | V _{GE(th)} | $I_C=400\mu A,\ V_{GE}=V_{CE}$ | 3 | 4 | 5 | |
| Zero gate voltage collector current | I _{CES} | V _{CE} =600V, V _{GE} =0V | | | 1.2 | μA |
| Gate-emitter leakage current | I _{GES} | V _{CE} =0V, V _{GE} =20V | | | 120 | nA |

DYNAMIC CHARACTERISTICS (tested at component):

| Parameter | Symbol | Canditions | Value | | | Unit |
|------------------------------|--------|----------------------|-------|------|------|-------|
| raiametei | Symbol | Conditions | min. | typ. | max. | Oilit |
| Input capacitance | Ciss | V _{CE} =25V | - | 800 | 960 | pF |
| Output capacitance | Coss | V _{GE} =0V | - | 84 | 100 | |
| Reverse transfer capacitance | Crss | f=1MHz | - | 52 | 63 | |

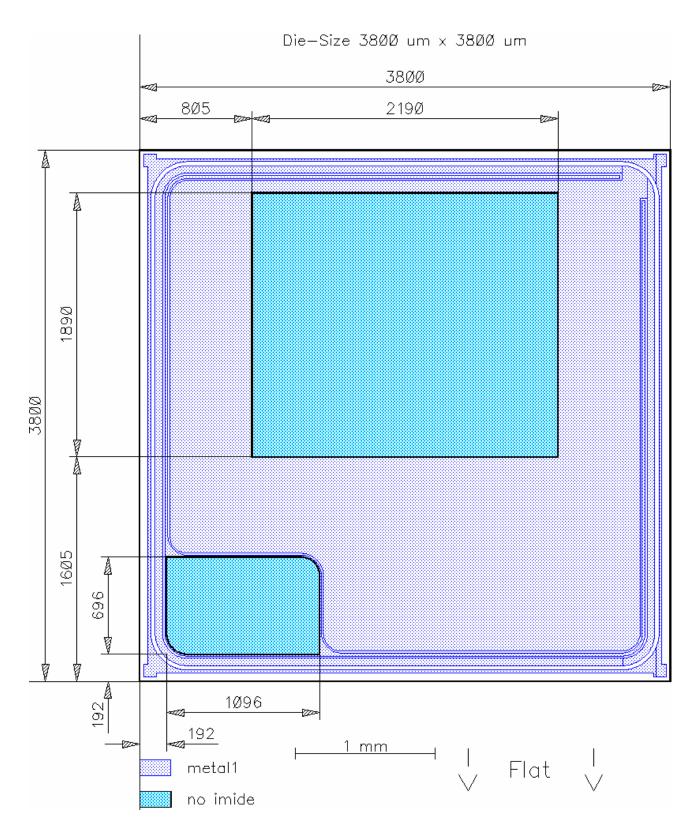
SWITCHING CHARACTERISTICS (tested at component), Inductive Load:

| Parameter | Symbol | Conditions 2) | Value | | | Unit |
|---------------------|--------------|--|-------|------|------|------|
| | | | min. | typ. | max. | Oill |
| Turn-on delay time | $t_{d(on)}$ | $T_{\rm j}$ =150°C $V_{\rm CC}$ =400V | - | 31 | 38 | ns |
| Rise time | t_{r} | $I_{\rm C}=15A$ | - | 23 | 28 | |
| Turn-off delay time | $t_{d(off)}$ | V_{GE} =+15/0V R_{G} =21 Ω | - | 261 | 313 | |
| Fall time | t_{f} | 7.6-2.22 | - | 54 | 65 | |

switching conditions different to 600V Standard IGBT 2, under comparable switching conditions 40% faster turnoff than Standard IGBT 2. Values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





SIGC14T60SNC

FURTHER ELECTRICAL CHARACTERISTICS:

| This chip data sheet refers to the | CCD4ENGO | Dealters (TO220 |
|------------------------------------|----------|-----------------|
| device data sheet | SGP15N60 | Package :TO220 |

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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